

S/N 10/613,260

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	MANHAEVE et al.	Examiner:	unknown
Serial No.:	10/613,260	Group Art Unit:	2858
Filed:	3 July 2003	Docket No.:	9997.69US01
Title:	DEVICE FOR MONITORING QUIESCENT CURRENT OF AN ELECTRONIC DEVICE		

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited in the United States Postal Service, as first class mail, with sufficient postage, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 27 October 2003.

By: 
Name: Heidi McCarty

INFORMATION DISCLOSURE STATEMENT (37 C.F.R. § 1.97(b))

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner.

This statement should be considered because it is submitted before the mailing date of a first Office Action on-the-merits. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F.R. § 1.98(a)(2), a copy of each document or other information listed on the enclosed Form 1449 is provided.

Applicant hereby brings attention to the Examiner that eight of the references listed were cited in a European Search Report dated 27 January 2003. A copy of the European Search Report is enclosed.

No representation is made that a reference is "prior art" within the meaning of 35 U.S.C. §§ 102 and 103 and Applicants reserve the right, pursuant to 37 C.F.R. § 1.131 or otherwise, to

establish that the reference(s) are not "prior art." Moreover, Applicants do not represent that a reference has been thoroughly reviewed or that any relevance of any portion of a reference is intended.

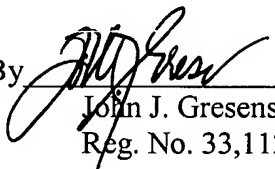
Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. 609, it is requested that the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

Please charge any additional fees or credit any overpayment to Deposit Account No. 13-2725.

Respectfully submitted,

MERCHANT & GOULD P.C.
P.O. Box 2903
Minneapolis, Minnesota 55402-0903
(612) 332-5300

Dated: 27 October 2003

By 
John J. Gresens
Reg. No. 33,112

JJG:hjm

FORM 1449 INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)	Docket Number: 9997.69US01	Application Number: 10/613,260
	Applicant: MANHAEVE et al.	
	Filing Date: 3 July 2003	Group Art Unit: 2858

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5 818 268	6 Oct. 1998	KIM et al.			
	6 414 511 B1	2 July 2002	JANSSEN et al.			
	5 914 615	22 June 1999	CHESS			
	5 483 170	9 Jan. 1996	BEASLEY et al.			

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	EP 0 811 850	10 Dec. 1997	EPO				
	EP 0 386 804	12 Sept. 1990	EPO				
	EP 0 672 911	20 Sept. 1995	EPO				
	WO 98/15844	16 April 1998	WIPO				
	EP 1 107 013	13 June 2001	EPO				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)	
	STRAKA et al. "A fully digital controlled off-chip I_{DDQ} measurement unit". Automation and Test in Europe, 1998. Proceedings Paris, France, Feb. 1998, Los Alamitos, CA, <i>IEEE Comput. Soc. US</i> , pp. 495-500 (23 Feb. 1998).
	SU et al. "Transient power supply current monitoring-a new test method for CMOS VLSI circuits". <i>Journal of Electronic Testing: Theory and Applications</i> , Vol. 6, No. 1, pp. 23-43 (1995).
	EICHENBERGER et al. "On Charge Injection in Analog MOS Switches and Dummy Switch Compensation Techniques". <i>IEEE Transactions on Circuits and Systems</i> , Vol. 37, No. 2, pp. 256-264 (Feb. 1990).
	EICHENBERGER et al. "Dummy Transistor Compensation of Analog MOS Switches". <i>IEEE Journal of Solid-State Circuits</i> , Vol. 24, No. 4, pp. 1143-1146 (August 1989).

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PATENT TRADEMARK OFFICE

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.	